

Search Notes

Application/Control No.

10/643,254

Examiner

Dimple N. Bodawala

Applicant(s)/Patent under
Reexamination

CRATHER ET AL.

Art Unit

1722

SEARCHED

Class	Subclass	Date	Examiner
425	8,67,68, 308-311	1/17/2007	DB
425	313,316	1/17/2007	DB
425	382R,464	1/17/2007	DB
264	8,37.12,	1/17/2007	DB
264	37.18	1/17/2007	DB
264	37.19	1/17/2007	DB
264	37.2	1/17/2007	DB
264	142,179	1/17/2007	DB
264	178R	1/17/2007	DB

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Update previous search	4/19/2007	DB